Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
(barcode)	10/022,622	KIM, KI-TAEK
	Examiner	Art Unit
	Feben M. Haile	2663

SEARCHED

Class	Subclass	Date	Examiner
370	389	2/3/2006	FH
370	395.1	2/3/2006	FH
370	395.7	2/3/2006	FH
370	395.71	2/3/2006	FH
370	412	2/3/2006	FH
370	413	2/3/2006	FH
370	395.6	2/3/2006	FH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Search: atm, cell, fifo, SOC, synchronization, buffer, memory, queue, storage, utopia, discard, remove	2/3/2006	FH
Updated Search	6/1/2006	FH